

| Ref # | Hits   | Search Query   | DBs   | Default Operator | Plurals | Time Stamp       |
|-------|--------|--|---|------------------|---------|------------------|
| L21   | 506185 | STI or isolation or LOCOS or (Buried adj oxide) or ((trench or groove) same (oxide or SiO <sub>2</sub> or SiO <sub>2</sub> ?sub\$3 or dielectric or insulat\$6)) | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2005/09/20 15:56 |
| L22   | 49632  | 21 same (void or defect\$6 or airgap or air or space or pore)  | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2005/09/20 15:57 |
| L23   | 9437   | 22 same (test\$6 or detect\$6 or sens\$6 or determin\$6 or measur\$6 or monitor\$6)  | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2005/09/20 15:59 |
| L24   | 7028   | 23 and (gate or wordline or line)  | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2005/09/20 15:59 |
| L25   | 3890   | 23 and ((gate or wordline or line) same (voltage or current or electric\$6 or potential))  | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2005/09/20 16:00 |
| L26   | 1535   | 25 and ((semiconductor or silicon) near20 (wafer or substrate))  | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2005/09/20 16:01 |
| L27   | 750    | 26 and ((test or active) near20 (region or area or structure))   | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2005/09/20 16:02 |
| L28   | 709    | 27 and (@ad<"20031118" or @rlad<"20031118")  | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2005/09/20 16:03 |

| Ref # | Hits | Search Query   | DBs   | Default Operator | Plurals | Time Stamp       |
|-------|------|--|---|------------------|---------|------------------|
| L4    | 1484 | (STI or (trench adj isolation)) same (void or air or airgap or gap)                              | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2005/09/20 10:37 |
| L5    | 106  | 4 and ((test\$6 or detect\$6 or measur\$6 or determin\$6) near20 (void or airgap or air or gap)) | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2005/09/20 10:38 |
| L6    | 99   | 5 and (@ad<"20031118" or @rlad<"20031118")   | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2005/09/20 10:38 |

| Ref # | Hits | Search Query   | DBs   | Default Operator | Plurals | Time Stamp       |
|-------|------|--|---|------------------|---------|------------------|
| L1    | 479  | (STI or (shallow adj trench adj isolation)) same void    | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2005/09/20 10:33 |
| L2    | 238  | 1 and (test\$6 or detect\$6 or measur\$6 or determin\$6) | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2005/09/20 10:34 |
| L3    | 219  | 2 and (@ad<="20031118" or @rlad<="20031118")             | US-PGPUB;<br>USPAT;<br>EPO; JPO;<br>DERWENT;<br>IBM_TDB | OR               | ON      | 2005/09/20 10:35 |

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Set Items Description

S1 677582 S ISOLATION? OR STI? ? OR DIELECTRIC?(5N)(GROOVE? ? OR CHANNEL? ? OR TRENCH??? OR GAP? ? OR OPENING?)  
S2 26581846 S DETECT? OR SENSING OR SENSE OR SENSES OR DETECT? OR MEASUR? OR MONITOR? OR IDENTIF? OR DETERMIN?  
S3 854550 S GATE OR GATES OR GATELINE?  
S4 14717390 S POTENTIAL OR VOLTAGE OR ELECTRIC? OR CURRENT? OR EMF? ?  
S5 2655 S S1 AND (S2 OR TEST????) AND S3 AND S4  
S6 5521796 S SEMICONDUCTOR? OR SEMI()CONDUCTOR? OR SUBSTRATE? OR WAFER?  
S7 1635 S S5 AND S6  
S8 180 S S1 (6N) (S2 OR TEST????) (6N) S3 (6N) S4  
S9 106 S S8 AND S6  
S10 81 S S9 AND PY<=2003  
S11 56 RD (unique items)  
S12 7 S S11 AND PD<=20031118  
S13 57669 S (S2 OR TEST????)(3N)(VOID? OR S1)  
S14 48606 S (S2 OR TEST????)(2N)(VOID? OR S1)  
S15 2152 S S6 AND S14  
S16 848 S S15 AND (S3 OR S4)  
S17 383 S S6 (10N)S14  
S18 38 S S17(10N)(S3 OR S4)  
S19 33 RD (unique items)  
S20 33 S S19 NOT S12  
S21 28 S S20 AND PY<=2003  
S22 54 S S11 NOT S20  
S23 47 S S22 NOT S12

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